supporting file:

Figure captions:

Fig. S1 (a) the continuously measured $I$-$V$ curves when the electron beam is on (In=1.98%).

Fig. S2 (a) the continuously measured $I$-$V$ curves when the electron beam is on (In=2.73%).

Fig. S3 (a) the continuously measured $I$-$V$ curves when the electron beam is on (In=3.33%).

Fig. S4 (a) the continuously measured $I$-$V$ curves when the electron beam is on (In=5.16%).

Fig. S5. Damage and breakdown of Sb-doped ZnO nanobelts under the irradiation of electron beam.
Fig. S1:

Current (nA) versus Voltage (V) graph showing measurements at different time points (0 min, 1 min, 2 min, 4 min, 5 min, 7 min).

In: 1.98%

Fig. S2:

Current (nA) versus Voltage (V) graph showing measurements at different time points (0 min, 2 min, 3 min, 4 min, 5 min, 6 min, 7 min, 10 min, 11 min, 12 min, 13 min, 14 min, 15 min, 16 min, 17 min, 18 min).

In: 2.73%
Fig. S3:

![Graph with current and voltage data for different time points, showing an increase in current with voltage over time.](image)

In: 3.33%

Fig. S4:

![Graph with current and voltage data for different time points, showing an increase in current with voltage over time.](image)

In: 5.16%
Fig.S5:

(a) $t = 15\text{s}$

(b) $t = 30\text{s}$

Single Crystalline

50nm

20nm